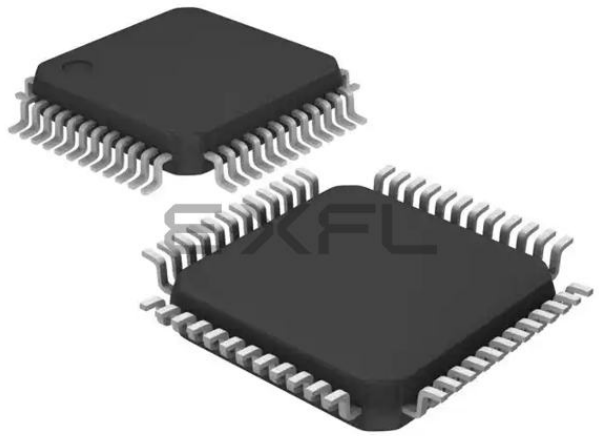

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	40MHz
Connectivity	I²C, LINbus, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	39
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	1.5K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/s9s08dn32f2clf

MC9S08DN60 Series Features

8-Bit HCS08 Central Processor Unit (CPU)

- 40-MHz HCS08 CPU (20-MHz bus)
- HC08 instruction set with added BGND instruction
- Support for up to 32 interrupt/reset sources

On-Chip Memory

- Flash read/program/erase over full operating voltage and temperature
  - MC9S08DN60 = 60K
  - MC9S08DN48 = 48K
  - MC9S08DN32 = 32K
  - MC9S08DN16 = 16K
- Up to 2K EEPROM in-circuit programmable memory; 8-byte single-page or 4-byte dual-page erase sector; Program and Erase while executing Flash; Erase abort
- Up to 2K random-access memory (RAM)

Power-Saving Modes

- Two very low power stop modes
- Reduced power wait mode
- Very low power real time interrupt for use in run, wait, and stop

Clock Source Options

- Oscillator (XOSC) — Loop-control Pierce oscillator; Crystal or ceramic resonator range of 31.25 kHz to 38.4 kHz or 1 MHz to 16 MHz
- Multi-purpose Clock Generator (MCG) — PLL and FLL modes (FLL capable of 1.5% deviation using internal temperature compensation); Internal reference clock with trim adjustment (trimmed at factory, with trim value stored in flash); External reference with oscillator/resonator options

System Protection

- Watchdog computer operating properly (COP) reset with option to run from backup dedicated 1-kHz internal clock source or bus clock
- Low-voltage detection with reset or interrupt; selectable trip points
- Illegal opcode detection with reset
- Illegal address detection with reset
- Flash block protect
- Loss-of-lock protection

Development Support

- Single-wire background debug interface
- On-chip, in-circuit emulation (ICE) with real-time bus capture

Peripherals

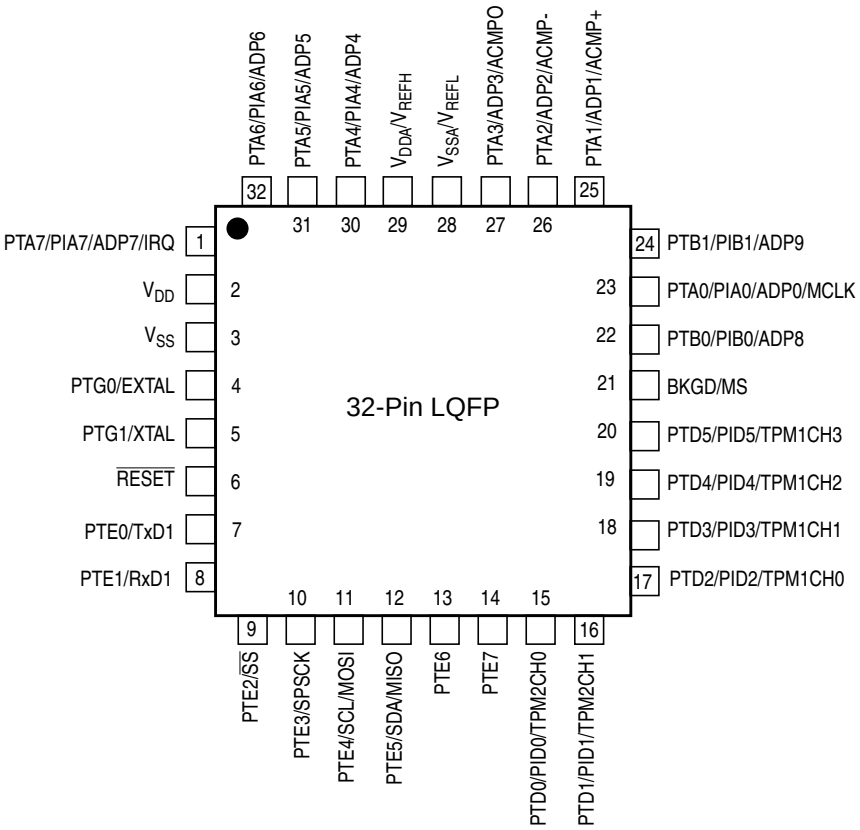
- **ADC** — 16-channel, 12-bit resolution, 2.5 µs conversion time, automatic compare function, temperature sensor, internal bandgap reference channel
- **ACMPx** — Two analog comparators with selectable interrupt on rising, falling, or either edge of comparator output; compare option to fixed internal bandgap reference voltage
- **SCI1** — One SCI supporting LIN 2.0 Protocol and SAE J2602 protocols; Full duplex non-return to zero (NRZ); Master extended break generation; Slave extended break detection; Wakeup on active edge
- **SPI** — Full-duplex or single-wire bidirectional; Double-buffered transmit and receive; Master or Slave mode; MSB-first or LSB-first shifting
- **IIC** — Up to 100 kbps with maximum bus loading; Multi-master operation; Programmable slave address; General Call Address; Interrupt driven byte-by-byte data transfer
- **TPMx** — One 6-channel (TPM1) and one 2-channel (TPM2); Selectable input capture, output compare, or buffered edge-aligned PWM on each channel
- **RTC** — (Real-time counter) 8-bit modulus counter with binary or decimal based prescaler; Real-time clock capabilities using external crystal and RTC for precise time base, time-of-day, calendar or task scheduling functions; Free running on-chip low power oscillator (1 kHz) for cyclic wake-up without external components

Input/Output

- 53 general-purpose input/output (I/O) pins and 1 input-only pin
- 24 interrupt pins with selectable polarity on each pin
- Hysteresis and configurable pull device on all input pins.
- Configurable slew rate and drive strength on all output pins.

Package Options

- 64-pin low-profile quad flat-pack (LQFP) — 10x10 mm
- 48-pin low-profile quad flat-pack (LQFP) — 7x7 mm
- 32-pin low-profile quad flat-pack (LQFP) — 7x7 mm



V_{REFH} and V_{REFL} are internally connected to V_{DDA} and V_{SSA}, respectively.

Figure 2-3. 32-Pin LQFP

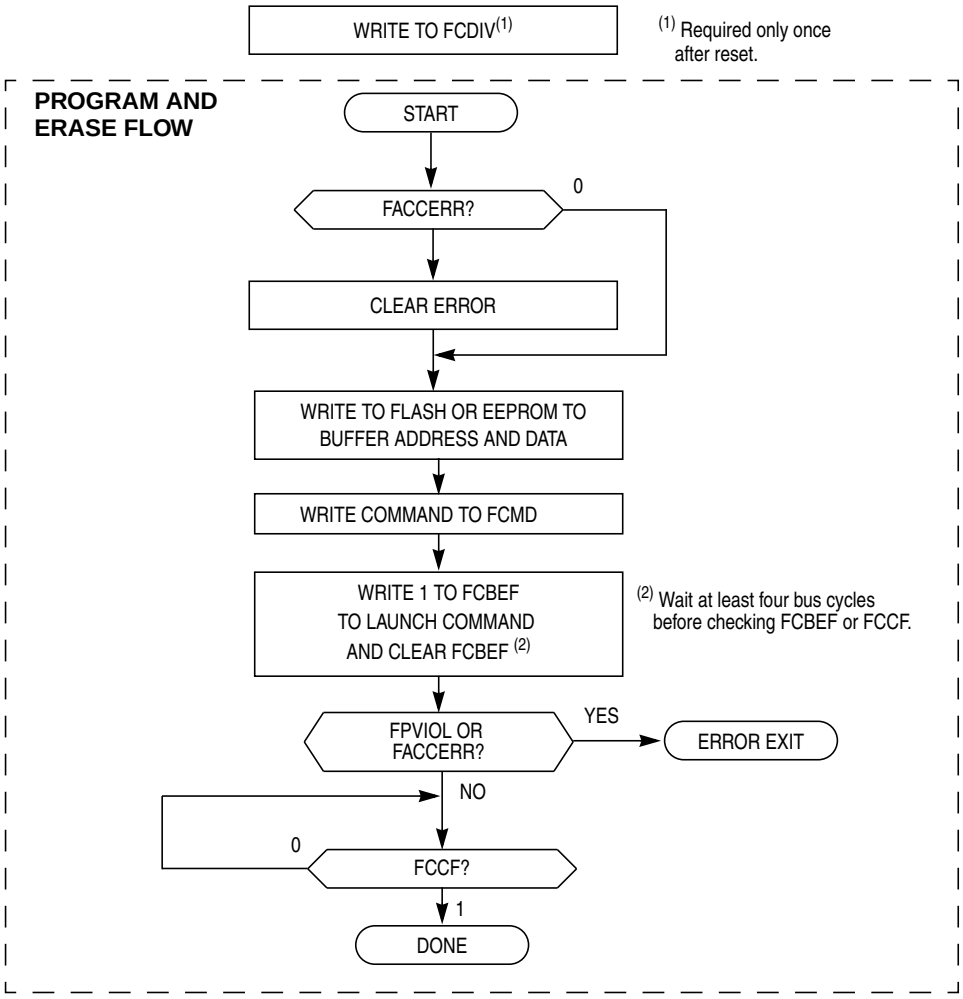


Figure 4-2. Program and Erase Flowchart

4.5.4 Burst Program Execution

The burst program command is used to program sequential bytes of data in less time than would be required using the standard program command. This is possible because the high voltage to the Flash array does not need to be disabled between program operations. Ordinarily, when a program or erase command is issued, an internal charge pump associated with the Flash memory must be enabled to supply high voltage to the array. Upon completion of the command, the charge pump is turned off. When a burst program command is issued, the charge pump is enabled and remains enabled after completion of the burst program operation if these two conditions are met:

- The next burst program command sequence has begun before the FCCF bit is set.
- The next sequential address selects a byte on the same burst block as the current byte being programmed. A burst block in this Flash memory consists of 32 bytes. A new burst block begins at each 32-byte address boundary.

The first byte of a series of sequential bytes being programmed in burst mode will take the same amount of time to program as a byte programmed in standard mode. Subsequent bytes will program in the burst

6.5.2.7 Port B Interrupt Pin Select Register (PTBPS)

	7	6	5	4	3	2	1	0
R W	PTBPS7	PTBPS6	PTBPS5	PTBPS4	PTBPS3	PTBPS2	PTBPS1	PTBPS0
Reset:	0	0	0	0	0	0	0	0

Figure 6-17. Port B Interrupt Pin Select Register (PTBPS)

Table 6-15. PTBPS Register Field Descriptions

Field	Description
7:0 PTBPS[7:0]	**Port B Interrupt Pin Selects** — Each of the PTBPSn bits enable the corresponding port B interrupt pin. 0 Pin not enabled as interrupt. 1 Pin enabled as interrupt.

6.5.2.8 Port B Interrupt Edge Select Register (PTBES)

	7	6	5	4	3	2	1	0
R W	PTBES7	PTBES6	PTBES5	PTBES4	PTBES3	PTBES2	PTBES1	PTBES0
Reset:	0	0	0	0	0	0	0	0

Figure 6-18. Port B Edge Select Register (PTBES)

Table 6-16. PTBES Register Field Descriptions

Field	Description
7:0 PTBES[7:0]	**Port B Edge Selects** — Each of the PTBESn bits serves a dual purpose by selecting the polarity of the active interrupt edge as well as selecting a pull-up or pull-down device if enabled. 0 A pull-up device is connected to the associated pin and detects falling edge/low level for interrupt generation. 1 A pull-down device is connected to the associated pin and detects rising edge/high level for interrupt generation.

6.5.4 Port D Registers

Port D is controlled by the registers listed below.

6.5.4.1 Port D Data Register (PTDD)

	7	6	5	4	3	2	1	0
R W	PTDD7	PTDD6	PTDD5	PTDD4	PTDD3	PTDD2	PTDD1	PTDD0
Reset:	0	0	0	0	0	0	0	0

Figure 6-24. Port D Data Register (PTDD)

Table 6-22. PTDD Register Field Descriptions

Field	Description
7:0 PTDD[7:0]	**Port D Data Register Bits** — For port D pins that are inputs, reads return the logic level on the pin. For port D pins that are configured as outputs, reads return the last value written to this register. Writes are latched into all bits of this register. For port D pins that are configured as outputs, the logic level is driven out the corresponding MCU pin. Reset forces PTDD to all 0s, but these 0s are not driven out the corresponding pins because reset also configures all port pins as high-impedance inputs with pull-ups/pull-downs disabled.

6.5.4.2 Port D Data Direction Register (PTDDD)

	7	6	5	4	3	2	1	0
R W	PTDDD7	PTDDD6	PTDDD5	PTDDD4	PTDDD3	PTDDD2	PTDDD1	PTDDD0
Reset:	0	0	0	0	0	0	0	0

Figure 6-25. Port D Data Direction Register (PTDDD)

Table 6-23. PTDDD Register Field Descriptions

Field	Description
7:0 PTDDD[7:0]	**Data Direction for Port D Bits** — These read/write bits control the direction of port D pins and what is read for PTDD reads. 0 Input (output driver disabled) and reads return the pin value. 1 Output driver enabled for port D bit n and PTDD reads return the contents of PTDDn.

6.5.6.3 Port F Pull Enable Register (PTFPE)

	7	6	5	4	3	2	1	0
R W	PTFPE7	PTFPE6	PTFPE5	PTFPE4	PTFPE3	PTFPE2	PTFPE1	PTFPE0
Reset:	0	0	0	0	0	0	0	0

Figure 6-39. Internal Pull Enable for Port F Register (PTFPE)

Table 6-37. PTFPE Register Field Descriptions

Field	Description
7:0 PTFPE[7:0]	**Internal Pull Enable for Port F Bits** — Each of these control bits determines if the internal pull-up device is enabled for the associated PTF pin. For port F pins that are configured as outputs, these bits have no effect and the internal pull devices are disabled. 0 Internal pull-up device disabled for port F bit n. 1 Internal pull-up device enabled for port F bit n.

NOTE

Pull-down devices only apply when using pin interrupt functions, when corresponding edge select and pin select functions are configured.

6.5.6.4 Port F Slew Rate Enable Register (PTFSE)

	7	6	5	4	3	2	1	0
R W	PTFSE7	PTFSE6	PTFSE5	PTFSE4	PTFSE3	PTFSE2	PTFSE1	PTFSE0
Reset:	0	0	0	0	0	0	0	0

Figure 6-40. Slew Rate Enable for Port F Register (PTFSE)

Table 6-38. PTFSE Register Field Descriptions

Field	Description
7:0 PTFSE[7:0]	**Output Slew Rate Enable for Port F Bits** — Each of these control bits determines if the output slew rate control is enabled for the associated PTF pin. For port F pins that are configured as inputs, these bits have no effect. 0 Output slew rate control disabled for port F bit n. 1 Output slew rate control enabled for port F bit n.

Note: Slew rate reset default values may differ between engineering samples and final production parts. Always initialize slew rate control to the desired value to ensure correct operation.

6.5.7 Port G Registers

Port G is controlled by the registers listed below.

6.5.7.1 Port G Data Register (PTGD)

	7	6	5	4	3	2	1	0
R	0	0	PTGD5	PTGD4	PTGD3	PTGD2	PTGD1	PTGD0
W								
Reset:	0	0	0	0	0	0	0	0

= Unimplemented or Reserved

Figure 6-42. Port G Data Register (PTGD)

Table 6-40. PTGD Register Field Descriptions

Field	Description
5:0 PTGD[5:0]	**Port G Data Register Bits** — For port G pins that are inputs, reads return the logic level on the pin. For port G pins that are configured as outputs, reads return the last value written to this register. Writes are latched into all bits of this register. For port G pins that are configured as outputs, the logic level is driven out the corresponding MCU pin. Reset forces PTGD to all 0s, but these 0s are not driven out the corresponding pins because reset also configures all port pins as high-impedance inputs with pull-ups disabled.

6.5.7.2 Port G Data Direction Register (PTGDD)

	7	6	5	4	3	2	1	0
R	0	0	PTGDD5	PTGDD4	PTGDD3	PTGDD2	PTGDD1	PTGDD0
W								
Reset:	0	0	0	0	0	0	0	0

= Unimplemented or Reserved

Figure 6-43. Port G Data Direction Register (PTGDD)

Table 6-41. PTGDD Register Field Descriptions

Field	Description
5:0 PTGDD[5:0]	**Data Direction for Port G Bits** — These read/write bits control the direction of port G pins and what is read for PTGD reads. 0 Input (output driver disabled) and reads return the pin value. 1 Output driver enabled for port G bit n and PTGD reads return the contents of PTGDn.

10.1.5 Temperature Sensor

To use the on-chip temperature sensor, the user must perform the following:

- Configure ADC for long sample with a maximum of 1 MHz clock
- Convert the bandgap voltage reference channel (AD27)
  - By converting the digital value of the bandgap voltage reference channel using the value of V_{BG} the user can determine V_{DD}. For value of bandgap voltage, see Section A.6, “DC Characteristics”.
- Convert the temperature sensor channel (AD26)
  - By using the calculated value of V_{DD}, convert the digital value of AD26 into a voltage, V_{TEMP}

Equation 10-1 provides an approximate transfer function of the temperature sensor.

$$Temp = 25 - ((V_{TEMP} - V_{TEMP25}) \div m) \qquad \textit{Eqn. 10-1}$$

where:

- V_{TEMP} is the voltage of the temperature sensor channel at the ambient temperature.
- V_{TEMP25} is the voltage of the temperature sensor channel at 25°C.
- m is the hot or cold voltage versus temperature slope in V/°C.

For temperature calculations, use the V_{TEMP25} and m values from the ADC Electricals table.

In application code, the user reads the temperature sensor channel, calculates V_{TEMP}, and compares to V_{TEMP25}. If V_{TEMP} is greater than V_{TEMP25} the cold slope value is applied in Equation 10-1. If V_{TEMP} is less than V_{TEMP25} the hot slope value is applied in Equation 10-1. To improve accuracy the user should calibrate the bandgap voltage reference and temperature sensor.

Calibrating at 25°C will improve accuracy to ± 4.5°C.

Calibration at three points, -40°C, 25°C, and 125°C will improve accuracy to ± 2.5°C. Once calibration has been completed, the user will need to calculate the slope for both hot and cold. In application code, the user would then calculate the temperature using Equation 10-1 as detailed above and then determine if the temperature is above or below 25°C. Once determined if the temperature is above or below 25°C, the user can recalculate the temperature using the hot or cold slope value obtained during calibration.

Table 10-6. ADCCFG Register Field Descriptions (continued)

Field	Description
3:2 MODE	Conversion Mode Selection. MODE bits are used to select between 12-, 10-, or 8-bit operation. See Table 10-8.
1:0 ADICLK	Input Clock Select. ADICLK bits select the input clock source to generate the internal clock ADCK. See Table 10-9.

Table 10-7. Clock Divide Select

ADIV	Divide Ratio	Clock Rate
00	1	Input clock
01	2	Input clock ÷ 2
10	4	Input clock ÷ 4
11	8	Input clock ÷ 8

Table 10-8. Conversion Modes

MODE	Mode Description
00	8-bit conversion (N=8)
01	12-bit conversion (N=12)
10	10-bit conversion (N=10)
11	Reserved

Table 10-9. Input Clock Select

ADICLK	Selected Clock Source
00	Bus clock
01	Bus clock divided by 2
10	Alternate clock (ALTCLK)
11	Asynchronous clock (ADACK)

10.3.8 Pin Control 1 Register (APCTL1)

The pin control registers disable the I/O port control of MCU pins used as analog inputs. APCTL1 is

Table 12-5. SPI Baud Rate Prescaler Divisor

SPPR2:SPPR1:SPPR0	Prescaler Divisor
0:0:0	1
0:0:1	2
0:1:0	3
0:1:1	4
1:0:0	5
1:0:1	6
1:1:0	7
1:1:1	8

Table 12-6. SPI Baud Rate Divisor

SPR2:SPR1:SPR0	Rate Divisor
0:0:0	2
0:0:1	4
0:1:0	8
0:1:1	16
1:0:0	32
1:0:1	64
1:1:0	128
1:1:1	256

12.4.4 SPI Status Register (SPIS)

This register has three read-only status bits. Bits 6, 3, 2, 1, and 0 are not implemented and always read 0. Writes have no meaning or effect.

	7	6	5	4	3	2	1	0
R	SPRF	0	SPTEF	MODF	0	0	0	0
W								
Reset	0	0	1	0	0	0	0	0

= Unimplemented or Reserved

Figure 12-8. SPI Status Register (SPIS)

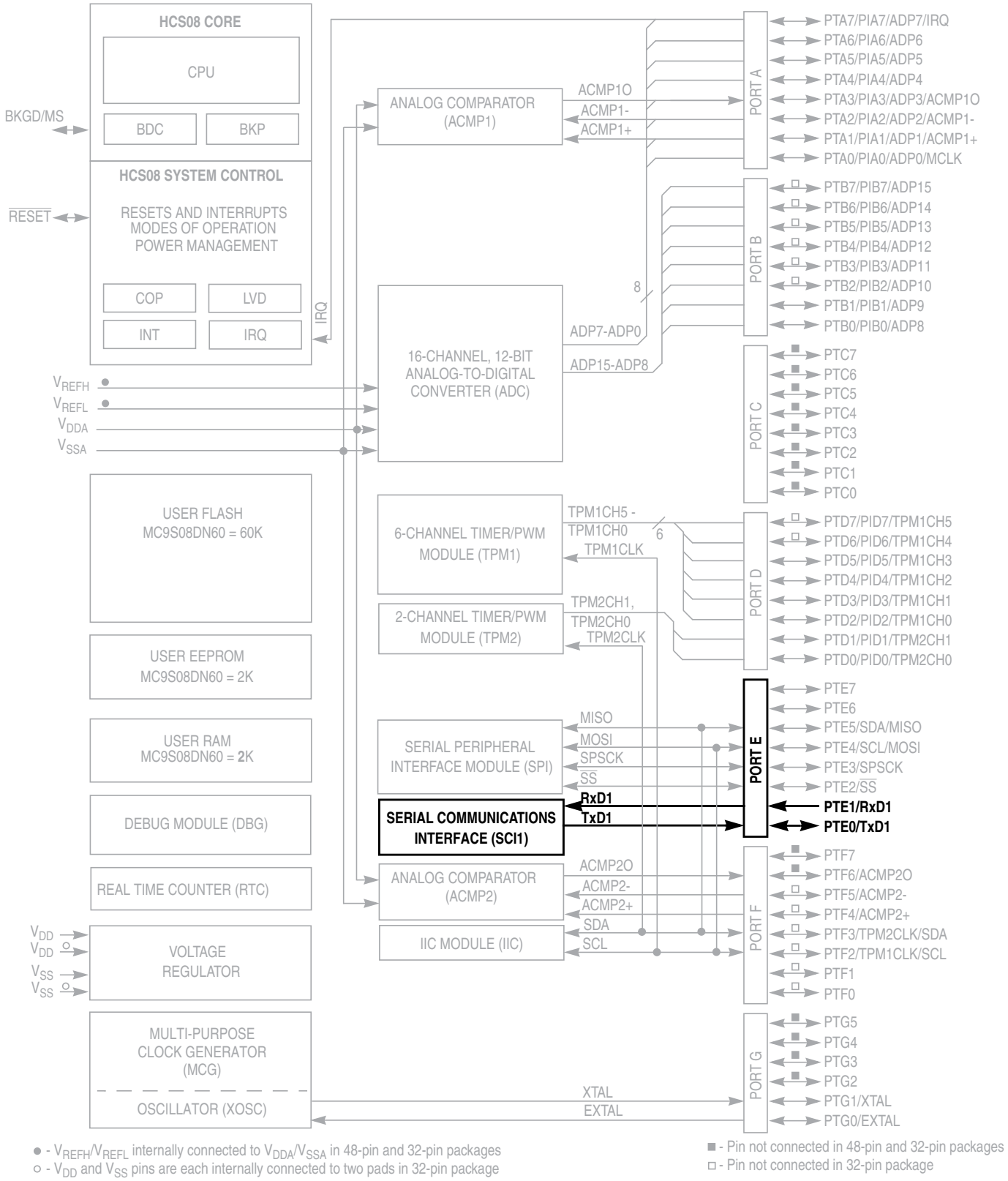


Figure 13-1. MC9S08DN60 Block Diagram

Table 13-7. SCI1C3 Field Descriptions (continued)

Field	Description
4 TXINV[1]	**Transmit Data Inversion** — Setting this bit reverses the polarity of the transmitted data output. 0 Transmit data not inverted 1 Transmit data inverted
3 ORIE	**Overrun Interrupt Enable** — This bit enables the overrun flag (OR) to generate hardware interrupt requests. 0 OR interrupts disabled (use polling). 1 Hardware interrupt requested when OR = 1.
2 NEIE	**Noise Error Interrupt Enable** — This bit enables the noise flag (NF) to generate hardware interrupt requests. 0 NF interrupts disabled (use polling). 1 Hardware interrupt requested when NF = 1.
1 FEIE	**Framing Error Interrupt Enable** — This bit enables the framing error flag (FE) to generate hardware interrupt requests. 0 FE interrupts disabled (use polling). 1 Hardware interrupt requested when FE = 1.
0 PEIE	**Parity Error Interrupt Enable** — This bit enables the parity error flag (PF) to generate hardware interrupt requests. 0 PF interrupts disabled (use polling). 1 Hardware interrupt requested when PF = 1.

1 Setting TXINV inverts the TxD output for all cases: data bits, start and stop bits, break, and idle.

13.2.7 SCI Data Register (SCI1D)

This register is actually two separate registers. Reads return the contents of the read-only receive data buffer and writes go to the write-only transmit data buffer. Reads and writes of this register are also involved in the automatic flag clearing mechanisms for the SCI status flags.

	7	6	5	4	3	2	1	0
R	R7	R6	R5	R4	R3	R2	R1	R0
W	T7	T6	T5	T4	T3	T2	T1	T0
Reset	0	0	0	0	0	0	0	0

Figure 13-11. SCI Data Register (SCI1D)

13.3 Functional Description

The SCI allows full-duplex, asynchronous, NRZ serial communication among the MCU and remote devices, including other MCUs. The SCI comprises a baud rate generator, transmitter, and receiver block. The transmitter and receiver operate independently, although they use the same baud rate generator. During normal operation, the MCU monitors the status of the SCI, writes the data to be transmitted, and processes received data. The following describes each of the blocks of the SCI.

13.3.1 Baud Rate Generation

As shown in Figure 13-12, the clock source for the SCI baud rate generator is the bus-rate clock.

EPWM mode
TPMxMODH:TPMxMODL = 0x0007
TPMxCnVH:TPMxCnVL = 0x0005

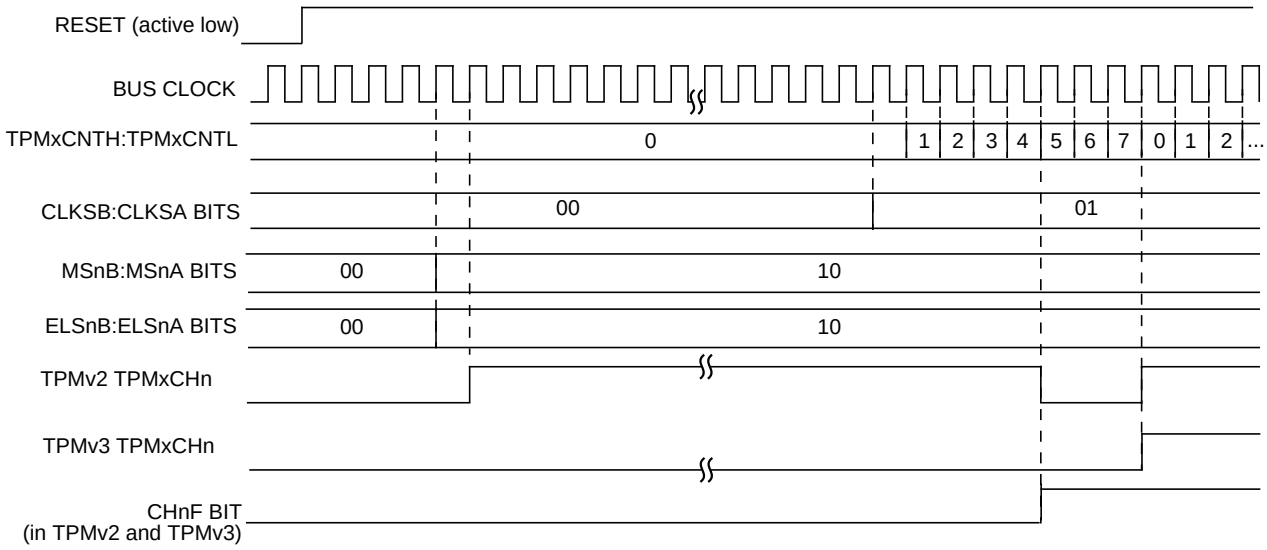


Figure 0-1. Generation of high-true EPWM signal by TPM v2 and v3 after the reset

EPWM mode
TPMxMODH:TPMxMODL = 0x0007
TPMxCnVH:TPMxCnVL = 0x0005

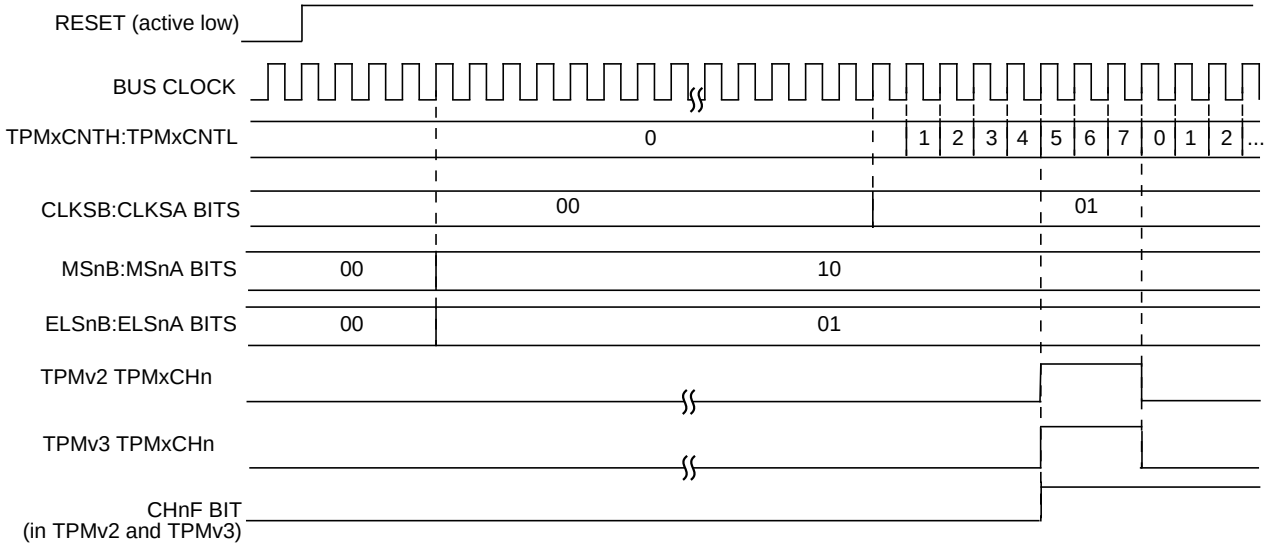


Figure 0-2. Generation of low-true EPWM signal by TPM v2 and v3 after the reset

The following procedure can be used in TPM v3 (when the channel pin is also a port pin) to emulate the high-true EPWM generated by TPM v2 after the reset.

Chapter 16
Development Support

16.1 Introduction

Development support systems in the HCS08 include the background debug controller (BDC) and the on-chip debug module (DBG). The BDC provides a single-wire debug interface to the target MCU that provides a convenient interface for programming the on-chip Flash and other nonvolatile memories. The BDC is also the primary debug interface for development and allows non-intrusive access to memory data and traditional debug features such as CPU register modify, breakpoints, and single instruction trace commands.

In the HCS08 Family, address and data bus signals are not available on external pins (not even in test modes). Debug is done through commands fed into the target MCU via the single-wire background debug interface. The debug module provides a means to selectively trigger and capture bus information so an external development system can reconstruct what happened inside the MCU on a cycle-by-cycle basis without having external access to the address and data signals.

16.1.1 Forcing Active Background

The method for forcing active background mode depends on the specific HCS08 derivative. For the MC9S08DN60, you can force active background after a power-on reset by holding the BKGD pin low as the device exits the reset condition. You can also force active background by driving BKGD low immediately after a serial background command that writes a one to the BDFR bit in the SBDFR register. If no debug pod is connected to the BKGD pin, the MCU will always reset into normal operating mode.

Figure 16-2 shows an external host transmitting a logic 1 or 0 to the BKGD pin of a target HCS08 MCU. The host is asynchronous to the target so there is a 0-to-1 cycle delay from the host-generated falling edge to where the target perceives the beginning of the bit time. Ten target BDC clock cycles later, the target senses the bit level on the BKGD pin. Typically, the host actively drives the pseudo-open-drain BKGD pin during host-to-target transmissions to speed up rising edges. Because the target does not drive the BKGD pin during the host-to-target transmission period, there is no need to treat the line as an open-drain signal during this period.

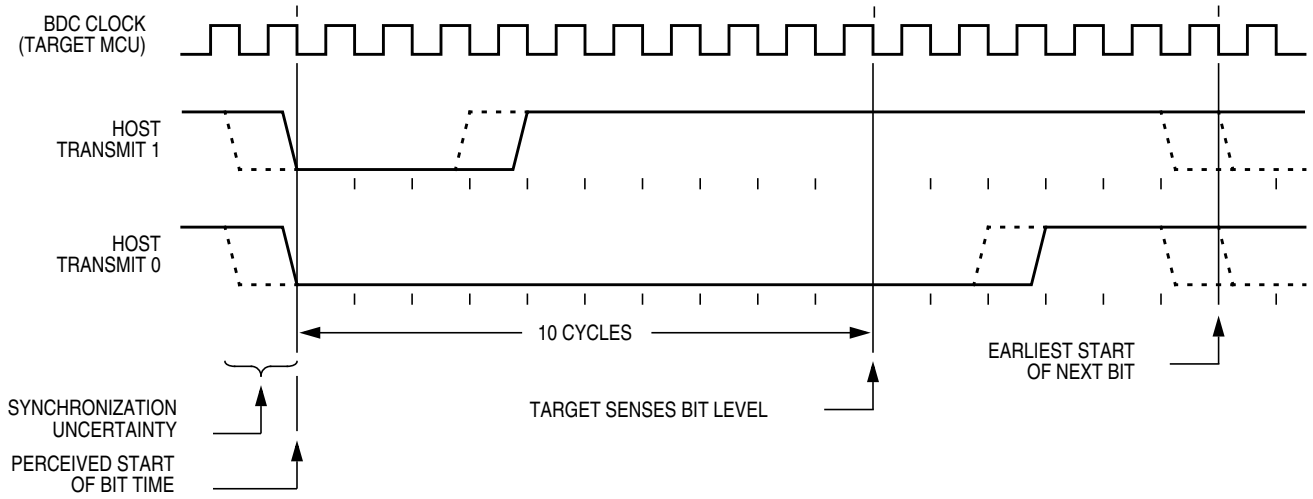


Figure 16-2. BDC Host-to-Target Serial Bit Timing

16.4.1.1 BDC Status and Control Register (BDCSCR)

This register can be read or written by serial BDC commands (READ_STATUS and WRITE_CONTROL) but is not accessible to user programs because it is not located in the normal memory map of the MCU.

	7	6	5	4	3	2	1	0
R	ENBDM	BDMACT	BKPTEN	FTS	CLKSW	WS	WSF	DVF
W								
Normal Reset	0	0	0	0	0	0	0	0
Reset in Active BDM:	1	1	0	0	1	0	0	0

= Unimplemented or Reserved

Figure 16-5. BDC Status and Control Register (BDCSCR)

Table 16-2. BDCSCR Register Field Descriptions

Field	Description
7 ENBDM	**Enable BDM (Permit Active Background Mode)** — Typically, this bit is written to 1 by the debug host shortly after the beginning of a debug session or whenever the debug host resets the target and remains 1 until a normal reset clears it. 0 BDM cannot be made active (non-intrusive commands still allowed) 1 BDM can be made active to allow active background mode commands
6 BDMACT	**Background Mode Active Status** — This is a read-only status bit. 0 BDM not active (user application program running) 1 BDM active and waiting for serial commands
5 BKPTEN	**BDC Breakpoint Enable** — If this bit is clear, the BDC breakpoint is disabled and the FTS (force tag select) control bit and BDCBKPT match register are ignored. 0 BDC breakpoint disabled 1 BDC breakpoint enabled
4 FTS	**Force/Tag Select** — When FTS = 1, a breakpoint is requested whenever the CPU address bus matches the BDCBKPT match register. When FTS = 0, a match between the CPU address bus and the BDCBKPT register causes the fetched opcode to be tagged. If this tagged opcode ever reaches the end of the instruction queue, the CPU enters active background mode rather than executing the tagged opcode. 0 Tag opcode at breakpoint address and enter active background mode if CPU attempts to execute that instruction 1 Breakpoint match forces active background mode at next instruction boundary (address need not be an opcode)
3 CLKSW	**Select Source for BDC Communications Clock** — CLKSW defaults to 0, which selects the alternate BDC clock source. 0 Alternate BDC clock source 1 MCU bus clock

Appendix A
Electrical Characteristics

A.1 Introduction

This section contains the most accurate electrical and timing information for the MC9S08DN60 Series of microcontrollers available at the time of publication.

A.2 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table A-1. Parameter Classifications

P	Those parameters are guaranteed during production testing on each individual device.
C	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
T	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
D	Those parameters are derived mainly from simulations.

NOTE

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

A.3 Absolute Maximum Ratings

Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the limits specified in Table A-2 may affect device reliability or cause permanent damage to the device. For functional operating conditions, refer to the remaining tables in this section.

NOTES:

1. DIMENSIONS ARE IN MILLIMETERS.

2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

3. DATUMS A, B AND D TO BE DETERMINED AT DATUM PLANE H.

4. DIMENSIONS TO BE DETERMINED AT SEATING PLANE C.

5. THIS DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED THE UPPER LIMIT BY MORE THAN 0.08 mm AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSION AND ADJACENT LEAD SHALL NOT BE LESS THAN 0.07 mm.

6. THIS DIMENSION DOES NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 mm PER SIDE. THIS DIMENSION IS MAXIMUM PLASTIC BODY SIZE DIMENSION INCLUDING MOLD MISMATCH.

7. EXACT SHAPE OF EACH CORNER IS OPTIONAL.

8. THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.1 mm AND 0.25 mm FROM THE LEAD TIP.

MECHANICAL OUTLINE	PRINT VERSION NOT TO SCALE

TITLE: 64LD LQFP, 10 X 10 X 1.4 PKG, 0.5 PITCH, CASE OUTLINE	DOCUMENT NO: 98ASS23234W	REV: E
	CASE NUMBER: 840F-02	11 AUG 2006
	STANDARD: JEDEC MS-026 BCD	